Search Notes

Applicant(s)/Patent Under Reexamination

BEAN ET AL.

Examiner

10786164

Chin-Shue, Alvin C

Art Unit

3634

SEARCHED

1	•		
Class	Subclass	Date	Examiner
182	18	4/27/07	acs
update.		10/10/07	acs

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

1	<u> </u>	<u> </u>		-
	Class	Subclass	Date	Examiner
ı	B	•		